Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/086,268	CHANG ET AL.	
Examiner	Art Unit	
Steven HD Nauven	2665	

SEARCHED				
Class	Subclass	Date	Examiner	
370	351-356, 401	2/1/2006	ST	
379	265.09			
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INTERFERENCE SEARCHED				
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